

Microwave nonlinear  
junction detector  
**«LORNET 36-mini»**

***USER MANUAL***

*CERTIFICATE*

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## Field of application

Nonlinear detector LORNET 36-mini is indispensable when conducting search operations in premises where the items containing electronic products are located with high density. It is also useful when searching for small electronic devices (1x2 cm).

## Technical characteristics

- **Type (power, duty ratio, average power) of the probing impulse signal:**  
Pulse (18W, 160, 112 mW) //  
CW (12W, 20W, 600mW)
- **Frequency of the probing signal:**  
3581.5 - 3607.5 MHz (13 MHz frequency selection is performed automatically according to the criterion of the minimum interference in the path of the receiver of the second harmonic)
- **Receiver frequency at 2 harmonic:**  
7163-7215 MHz
- **Receiver frequency at 3 harmonic:** 10744.5-10822.5 MHz
- Transmit power can be adjusted both automatically and manually in the range of 30 dB in steps of 3 dB
- The option to adjust attenuator of the receivers 15dB in steps of 3dB
- The option of audio control of 2 or 3 harmonics separately to the internal speaker or wireless headphones

- **Sensitivity at 2 and 3 harmonics (without antenna gain):**  
minus 110dBm (-140 dBW)
- **Dynamic range:** more than 30 dB
- **The angle of the directional pattern of the antenna (1 harmonics):** 16 degrees
- Laser illumination of the directional pattern center
- **Battery life at max. power of the probing signal:** 3hours
- **Dimensions in operation/transport:**  
52x25x14/27x25x14 cm
- **Overall weight of the product under operation:** less than 1000 grams
- **Operating temperature range:** +5 ... +40 °C

## **Main competitive advantages**

- Considering the parameters of detection range, selection and the accuracy of spatial localization of semiconductor devices at the distances of up to 2 meters away from the technical characteristics of the device fully correspond to Lornet-36 specifications.
- The application of microwave range provided the unique opportunities to detect semiconductor elements hidden by different materials (it detects through cracks, unearthed screens, reflections from smooth surfaces, SIM card is detected at the distance of 1 meter, etc.).
- Both narrow beam of directional pattern and laser pointer make it possible to conduct spatial selection

- of various semiconductor devices with high accuracy.
- Very useful when examining reflected ceilings, as it does not require constant use of ladder.
  - Control and indication of operation is carried out in the same way as in the products Lornet, Lornet-24 and Lornet-36 (including automatic and manual changes in power of the probing signal in impulse mode).
  - Application of the latest technologies and materials, ergonomics.
  - Convenient display and control elements, easy to operate, light weight.
  - Significantly reduced electromagnetic impact on the operator because of high duty ratio of the probing impulses and significant reduction of undesirable radiation towards the operator.
  - The use of wireless headphones

## **In box**

- Receiver-transmitter unit with control unit and built-in battery container
- Two changeable Li-Ion batteries
- Container for battery charging
- Charger for receiver-transmitter unit 220V (CH1)
- Wireless accessories including: receiving device, earphones and charger 220V (CH2)
- Technical Description & User manual, Certificate (in one piece)
- Package